

100315 Low-Skew Quad Clock Driver

General Description

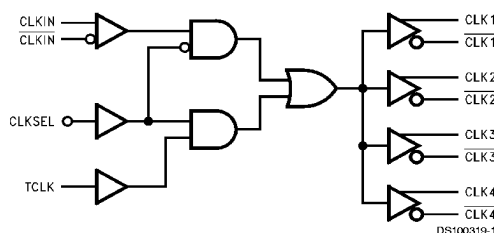
The 100315 contains four low skew differential drivers, designed for generation of multiple, minimum skew differential clocks from a single differential input. This device also has the capability to select a secondary single-ended clock source for use in lower frequency system level testing. The 100315 is a 300 Series redesign of the 100115 clock driver.

- Differential inputs and outputs
- Secondary clock available for system level testing
- 2000V ESD protection
- Voltage compensated operating range: -4.2V to -5.7V
- Standard Microcircuit Drawing (SMD) 5962-9469601

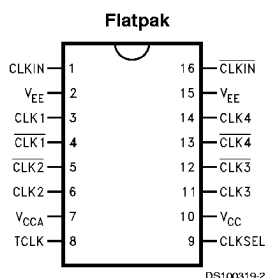
Features

- Low output to output skew (≤ 50 ps)

Logic Diagram



Connection Diagram



Pin Names	Description
CLKIN, $\overline{\text{CLKIN}}$	Differential Clock Inputs
CLK ₁₋₄ , $\overline{\text{CLK}}_{1-4}$	Differential Clock Outputs
TCLK	Test Clock Input (Note 1)
CLKSEL	Clock Input Select (Note 1)

Note 1: TCLK and CLKSEL are single-ended inputs, with internal 50 k Ω pull-down resistors.

Truth Table

CLKSEL	CLKIN	$\overline{\text{CLKIN}}$	TCLK	CLK _N	$\overline{\text{CLK}}_{\text{N}}$
L	L	H	X	L	H
L	H	L	X	H	L
H	X	X	L	L	H
H	X	X	H	H	L

L = Low Voltage Level
H = High Voltage Level
X = Don't Care

Absolute Maximum Ratings (Note 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Above which the useful life may be impaired

Storage Temperature -65°C to $+150^{\circ}\text{C}$

Maximum Junction Temperature (T_J)

Ceramic $+175^{\circ}\text{C}$

Case Temperature under Bias (T_C) -55°C to $+125^{\circ}\text{C}$

V_{EE} Pin Potential to Ground Pin -7.0V to $+0.5\text{V}$

Input Voltage (DC) V_{CC} to $+0.5\text{V}$

Output Current (DC Output HIGH) -50mA

Operating Range (Note 2)

-5.7V to -4.2V

ESD (Note 3)

$\geq 2000\text{V}$

Recommended Operating Conditions

Case Temperature (T_C)

Military

-55°C to $+125^{\circ}\text{C}$

Supply Voltage (V_{EE})

-5.7V to -4.2V

Note 2: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: ESD testing conforms to MIL-STD-883, Method 3015.

Military Version DC Electrical Characteristics

$V_{EE} = -4.2\text{V}$ to -5.7V , $V_{CC} = V_{CCA} = \text{GND}$ (Note 6)

Symbol	Parameter	Min	Typ	Max	Units	T_C	Conditions	Notes
V_{OH}	Output HIGH Voltage	-1025		-870	mV	0°C to $+125^{\circ}\text{C}$	$V_{IN} = V_{IH(\text{Max})}$ or $V_{IL(\text{Min})}$	Loading with 50Ω to -2.0V (Notes 4, 5, 6)
		-1085		-870	mV	-55°C to $+125^{\circ}\text{C}$		
V_{OL}	Output LOW Voltage	-1830		-1620	mV	0°C to $+125^{\circ}\text{C}$	$V_{IN} = V_{IH(\text{Min})}$ or $V_{IL(\text{Max})}$	Loading with 50Ω to -2.0V (Notes 4, 5, 6)
		-1830		-1555	mV	-55°C to $+125^{\circ}\text{C}$		
V_{OHC}	Output HIGH Voltage	-1035			mV	0°C to $+125^{\circ}\text{C}$	$V_{IN} = V_{IH(\text{Min})}$ or $V_{IL(\text{Max})}$	Loading with 50Ω to -2.0V (Notes 4, 5, 6)
		-1085			mV	-55°C to $+125^{\circ}\text{C}$		
V_{OLC}	Output LOW Voltage			-1610	mV	0°C to $+125^{\circ}\text{C}$	$V_{IN} = V_{IH(\text{Min})}$ or $V_{IL(\text{Max})}$	Loading with 50Ω to -2.0V (Notes 4, 5, 6)
				-1555	mV	-55°C to $+125^{\circ}\text{C}$		

DC Electrical Characteristics

$V_{EE} = -4.2\text{V}$ to -5.7V , $V_{CC} = V_{CCA} = \text{GND}$ (Note 6)

Symbol	Parameter	Min	Typ	Max	Units	T_C	Conditions	Notes
V_{DIFF}	Input Voltage Differential	150			mV	-55°C to $+125^{\circ}\text{C}$	Required for Full Output Swing	(Notes 4, 5, 6)
V_{CM}	Common Mode Voltage	$V_{CC} - 2.0$		$V_{CC} - 0.5$	V	-55°C to $+125^{\circ}\text{C}$		(Notes 4, 5, 6)
V_{IH}	Single-Ended Input High Voltage	-1165		-870	mV	-55°C to $+125^{\circ}\text{C}$	Guaranteed HIGH Signal for All Inputs	(Notes 4, 5, 6, 7)
V_{IL}	Single-Ended Input Low Voltage	-1830		-1475	mV	-55°C to $+125^{\circ}\text{C}$	Guaranteed LOW Signal for All Inputs	(Notes 4, 5, 6, 7)
I_{IH}	Input HIGH Current $\text{CLKIN}, \overline{\text{CLKIN}}$			150	μA	-55°C to $+125^{\circ}\text{C}$	$V_{IN} = V_{IH(\text{Max})}$	(Notes 4, 5, 6)
	TCLK			450	μA			
	CLKSEL			380	μA			
I_{CBO}	Input Leakage Current	-10			μA	-55°C to $+125^{\circ}\text{C}$	$V_{IN} = V_{EE}$	(Notes 4, 5, 6)
I_{EE}	Power Supply Current, Normal	-80		-25	mA	-55°C to $+125^{\circ}\text{C}$		(Notes 4, 5, 6)

Note 4: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals -55°C), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

DC Electrical Characteristics (Continued)

Note 5: Screen tested 100% on each device at -55°C , $+25^{\circ}\text{C}$, and $+125^{\circ}\text{C}$, Subgroups 1, 2, 3, 7, and 8.

Note 6: Sample tested (Method 5005, Table I) on each manufactured lot at -55°C , $+25^{\circ}\text{C}$, and $+125^{\circ}\text{C}$, Subgroups A1, 2, 3, 7, and 8.

Note 7: Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

AC Electrical Characteristics

$V_{EE} = -4.2\text{V}$ to -5.7V , $V_{CC} = V_{CCA} = \text{GND}$

Symbol	Parameter	$T_C = -55^{\circ}\text{C}$		$T_C = +25^{\circ}\text{C}$		$T_C = +125^{\circ}\text{C}$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
t_{PLH} t_{PHL}	Propagation Delay CLKIN, $\overline{\text{CLKIN}}$ to $\text{CLK}_{(1-4)}$, $\overline{\text{CLK}}_{(1-4)}$	0.58	0.88	0.63	0.88	0.72	1.02	ns	Figures 1, 2	(Notes 8, 9, 10)
t_{PLH} t_{PHL}	Propagation Delay, TCLK to $\text{CLK}_{(1-4)}$, $\overline{\text{CLK}}_{(1-4)}$	0.30	1.60	0.30	1.50	0.40	1.70	ns		
t_{S-G-G}	Skew Gate to Gate (Note 12)	120		100		120		ps		
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.30	0.90	0.25	0.85	0.20	0.85	ns		(Note 10)

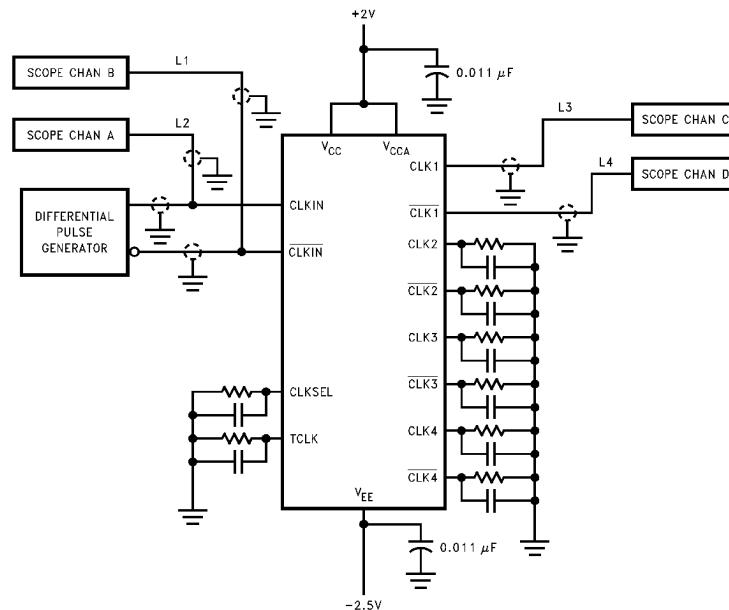
Note 8: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals -55°C , then testing immediately after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 9: Screen tested 100% on each device at $+25^{\circ}\text{C}$ temperature only, Subgroup A9.

Note 10: Sample tested (Method 5005, Table I) on each manufactured lot at $+25^{\circ}\text{C}$, Subgroup A9, and at $+125^{\circ}\text{C}$ and -55°C temperatures, Subgroups A10 and A11.

Note 11: Not tested at $+25^{\circ}\text{C}$, $+125^{\circ}\text{C}$ and -55°C temperature (design characterization data).

Note 12: Maximum output skew for any one device.



Note 13: Shown for testing CLKIN to CLK1 in the differential mode.

Note 14: L1, L2, L3 and L4 = equal length 50Ω impedance lines.

Note 15: All unused inputs and outputs are loaded with 50Ω in parallel with $\leq 3\text{ pF}$ to GND.

Note 16: Scope should have 50Ω input terminator internally.

FIGURE 1. AC Test Circuit

AC Electrical Characteristics (Continued)

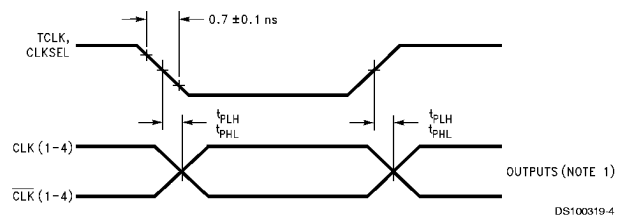


FIGURE 2. Propagation Delay, TCLK, CLKSEL to Outputs

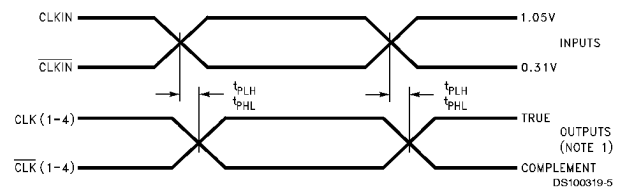
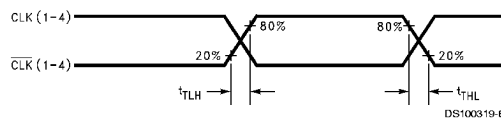
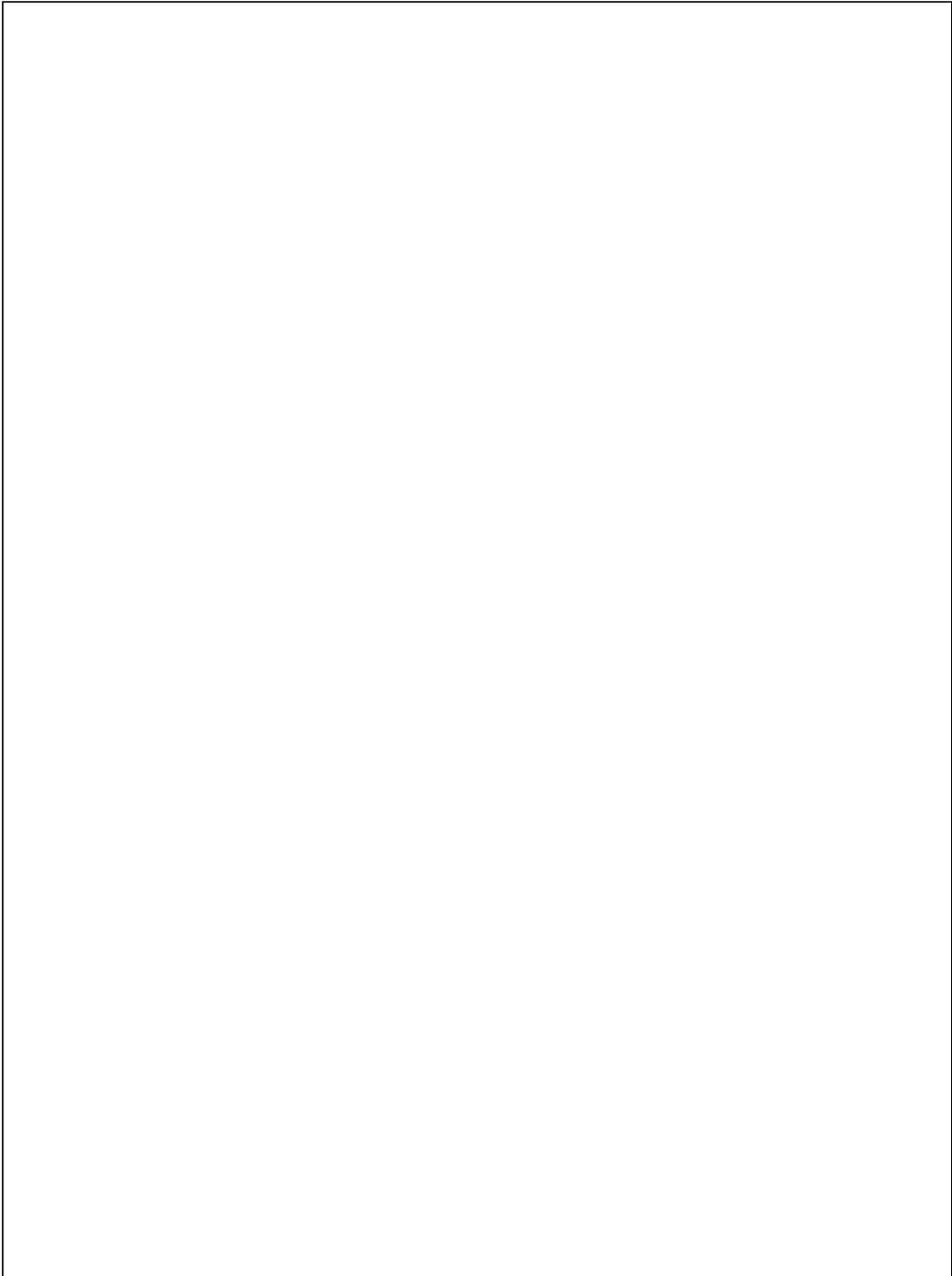


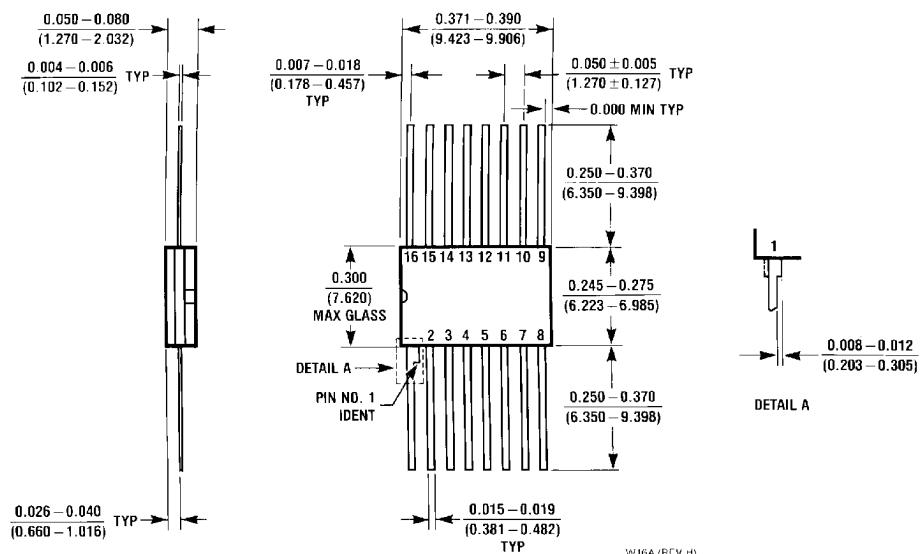
FIGURE 3. Propagation Delay, CLKIN/CLKIN to Outputs



Note 17: The output to output skew, which is defined as the difference in the propagation delays between each of the four outputs on any one 100115 shall not exceed 75 ps.

FIGURE 4. Transition Times



Physical Dimensions inches (millimeters) unless otherwise noted

16 Lead Ceramic Flatpak (F)
NS Package Number W16A

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National Semiconductor Corporation
Americas
Tel: 1-800-272-9959
Fax: 1-800-737-7018
Email: support@nsc.com

www.national.com

National Semiconductor Europe
Fax: +49 (0) 1 80-530 85 86
Email: europe.support@nsc.com
Deutsch Tel: +49 (0) 1 80-530 85 85
English Tel: +49 (0) 1 80-532 78 32
Français Tel: +49 (0) 1 80-532 93 58
Italiano Tel: +49 (0) 1 80-534 16 80

National Semiconductor Asia Pacific Customer Response Group
Tel: 65-2544466
Fax: 65-2504466
Email: sea.support@nsc.com

National Semiconductor Japan Ltd.
Tel: 81-3-5620-6175
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